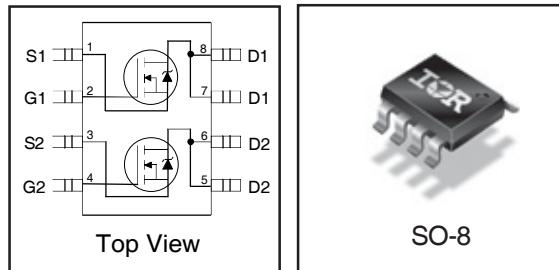


HEXFET® Power MOSFET

V_{DS}	12	V
R_{DS(on)} max (@V _{GS} = 4.5V)	15	mΩ
Q_g (typical)	17	nC
I_D (@T _A = 25°C)	10	A



SO-8

Applications

- High Frequency 3.3V and 5V input Point-of-Load Synchronous Buck Converters for Netcom and Computing Applications
- Power Management for Netcom, Computing and Portable Applications

Features

Industry-standard pinout SO-8 Package
Compatible with Existing Surface Mount Techniques
RoHS Compliant, Halogen-Free
MSL1, Industrial qualification

Benefits

Multi-Vendor Compatibility
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRF7910PbF-1	SO-8	Tube/Bulk	95	IRF7910PbF-1
		Tape and Reel	4000	IRF7910TRPbF-1

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
V _{DS}	Drain-Source Voltage	12	V
V _{GS}	Gate-to-Source Voltage	± 12	V
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 4.5V	10	A
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 4.5V	7.9	
I _{DM}	Pulsed Drain Current①	79	
P _D @ T _A = 25°C	Maximum Power Dissipation④	2.0	W
P _D @ T _A = 70°C	Maximum Power Dissipation④	1.3	W
	Linear Derating Factor	16	mW/°C
T _J , T _{STG}	Junction and Storage Temperature Range	-55 to + 150	°C

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R _{θJL}	Junction-to-Drain Lead	—	42	°C/W
R _{θJA}	Junction-to-Ambient ④	—	62.5	

Notes ① through ④ are on page 8

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	12	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.01	—	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	11.5	15	$\text{m}\Omega$	$V_{GS} = 4.5\text{V}, I_D = 8.0\text{A}$ ③
		—	20	50		$V_{GS} = 2.8\text{V}, I_D = 5.0\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	0.6	—	2.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	100	μA	$V_{DS} = 9.6\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 9.6\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 12\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -12\text{V}$

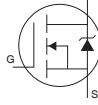
Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	18	—	—	S	$V_{DS} = 6.0\text{V}, I_D = 8.0\text{A}$
Q_g	Total Gate Charge	—	17	26	nC	$I_D = 8.0\text{A}$
Q_{gs}	Gate-to-Source Charge	—	4.4	—		$V_{DS} = 6.0\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	5.2	—		$V_{GS} = 4.5\text{V}$
Q_{oss}	Output Gate Charge	—	16	—		$V_{GS} = 0\text{V}, V_{DS} = 10\text{V}$
$t_{d(on)}$	Turn-On Delay Time	—	9.4	—	ns	$V_{DD} = 6.0\text{V}$
t_r	Rise Time	—	22	—		$I_D = 8.0\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	16	—		$R_G = 1.8\Omega$
t_f	Fall Time	—	6.3	—		$V_{GS} = 4.5\text{V}$ ③
C_{iss}	Input Capacitance	—	1730	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	1340	—		$V_{DS} = 6.0\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	330	—		$f = 1.0\text{MHz}$

Avalanche Characteristics

Symbol	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	100	mJ
I_{AR}	Avalanche Current ①	—	8.0	A

Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	1.8	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	79		
V_{SD}	Diode Forward Voltage	—	0.85	1.3	V	$T_J = 25^\circ\text{C}, I_S = 8.0\text{A}, V_{GS} = 0\text{V}$ ③
		—	0.70	—		$T_J = 125^\circ\text{C}, I_S = 8.0\text{A}, V_{GS} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	50	75	ns	$T_J = 25^\circ\text{C}, I_F = 8.0\text{A}, V_R = 12\text{V}$
Q_{rr}	Reverse Recovery Charge	—	60	90	nC	$di/dt = 100\text{A}/\mu\text{s}$ ③
t_{rr}	Reverse Recovery Time	—	51	77	ns	$T_J = 125^\circ\text{C}, I_F = 8.0\text{A}, V_R = 12\text{V}$
Q_{rr}	Reverse Recovery Charge	—	60	90	nC	$di/dt = 100\text{A}/\mu\text{s}$ ③

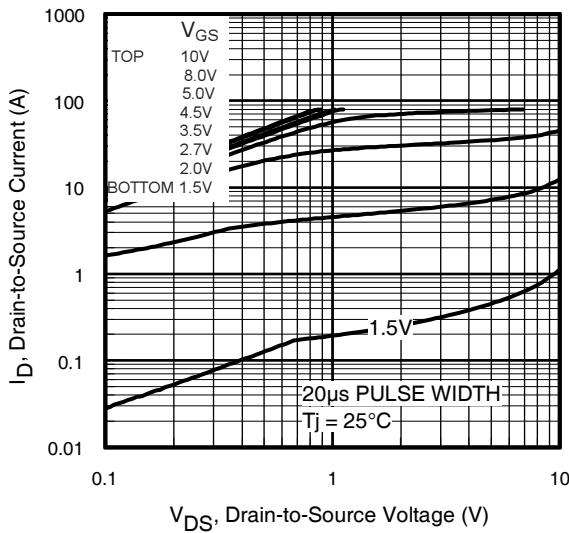


Fig 1. Typical Output Characteristics

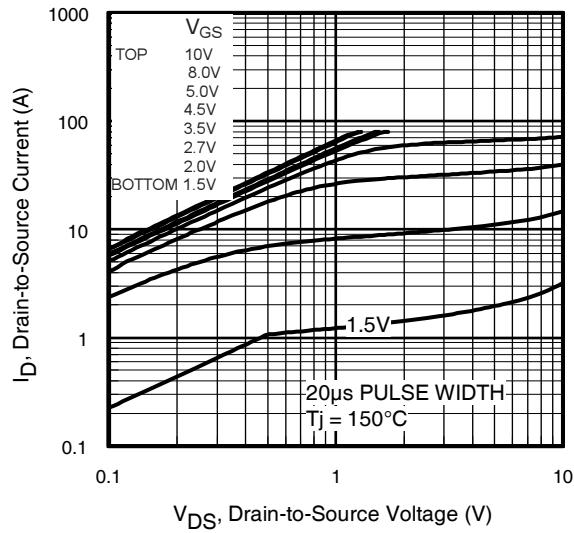


Fig 2. Typical Output Characteristics

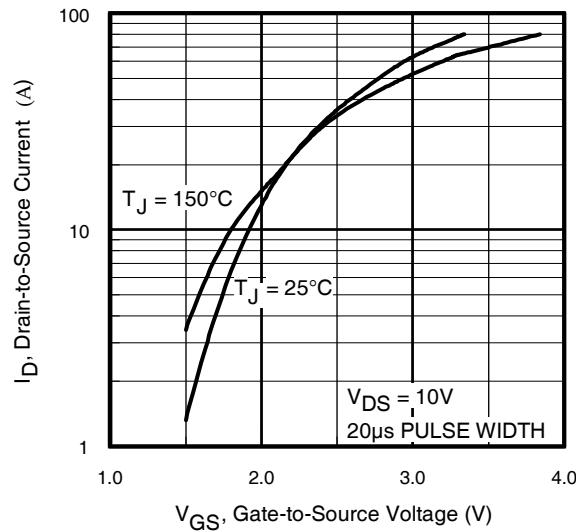


Fig 3. Typical Transfer Characteristics

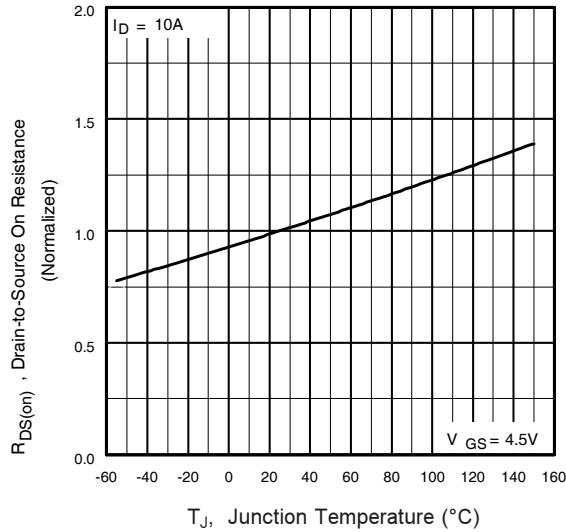


Fig 4. Normalized On-Resistance Vs. Temperature

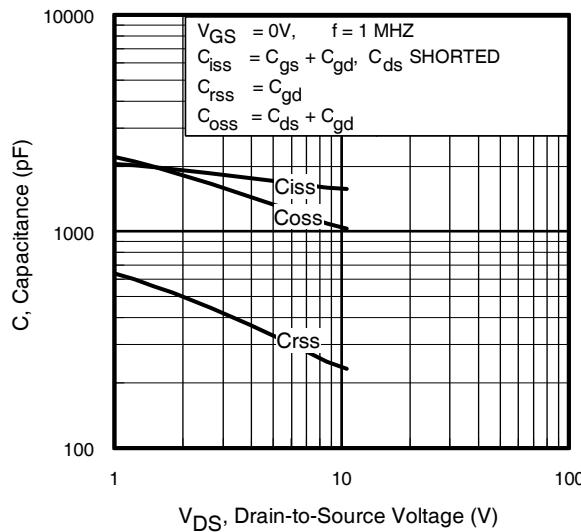


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

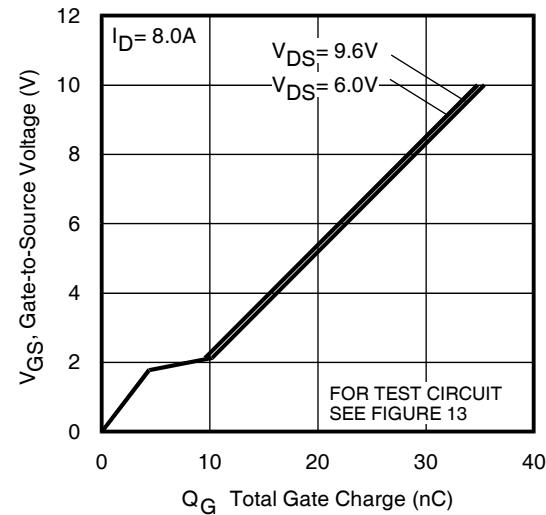


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

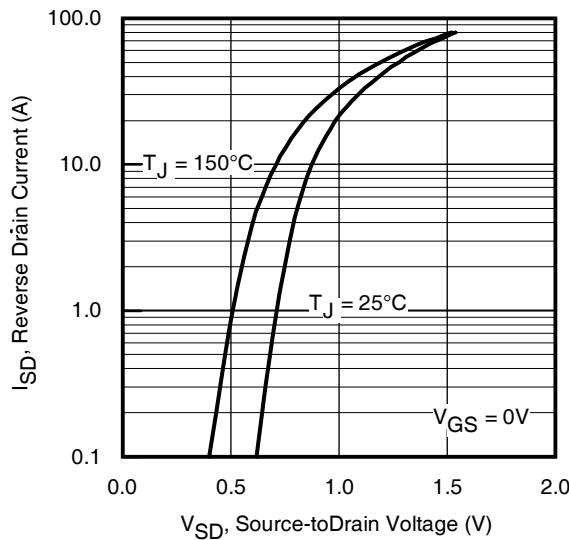


Fig 7. Typical Source-Drain Diode
Forward Voltage

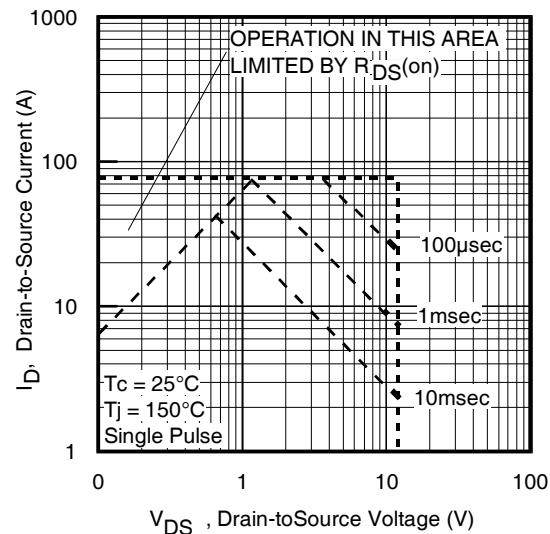


Fig 8. Maximum Safe Operating Area

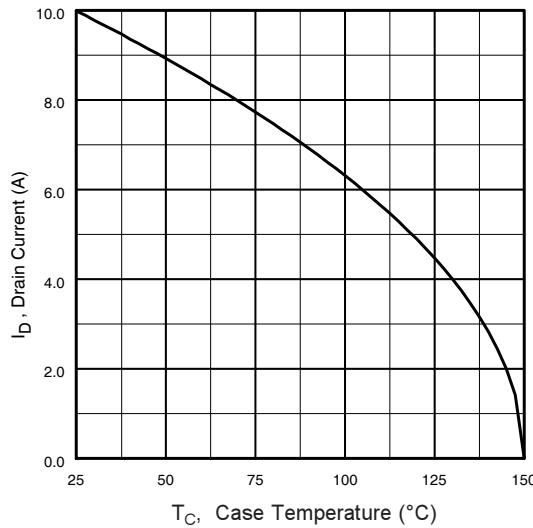


Fig 9. Maximum Drain Current Vs. Ambient Temperature

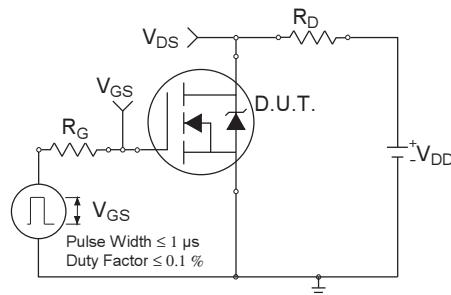


Fig 10a. Switching Time Test Circuit

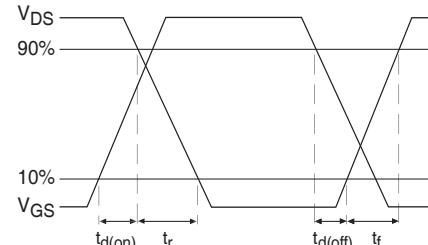


Fig 10b. Switching Time Waveforms

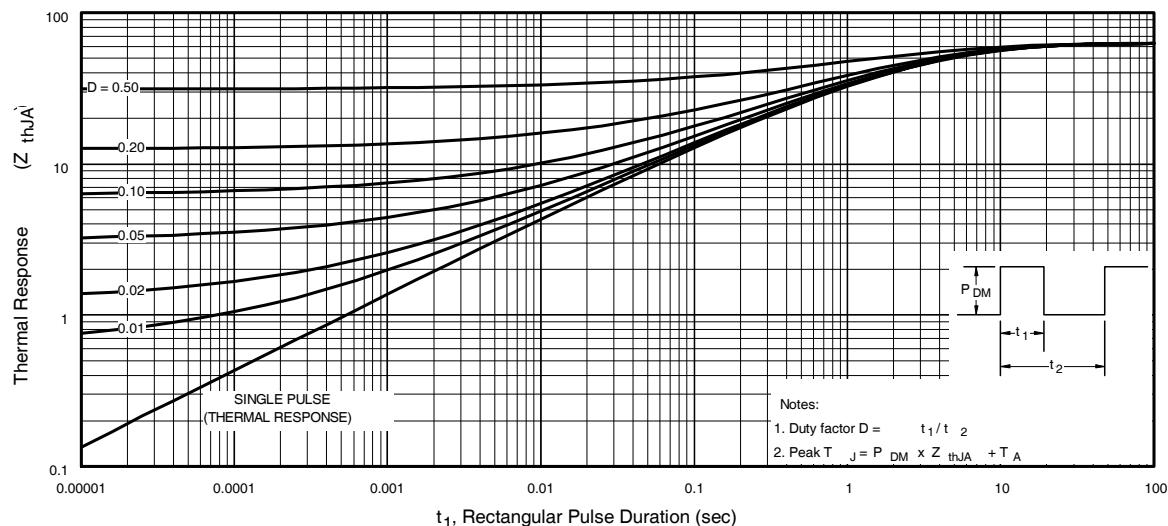
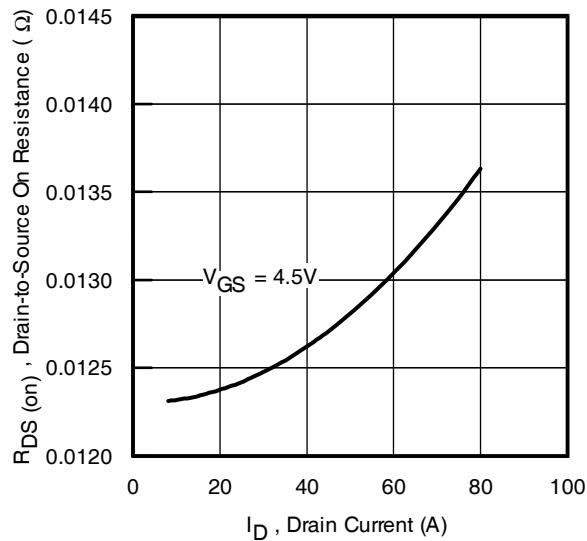
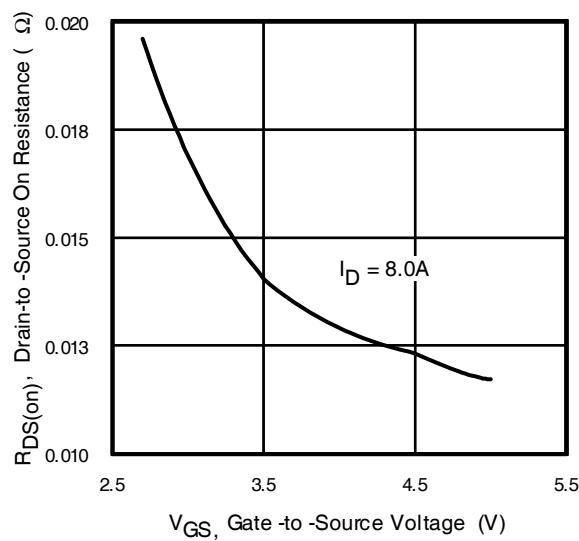
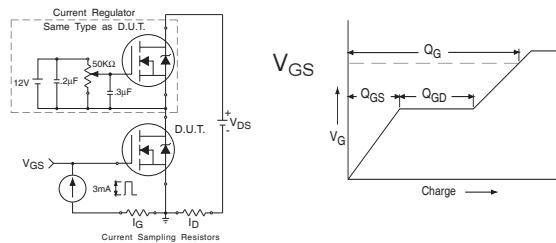
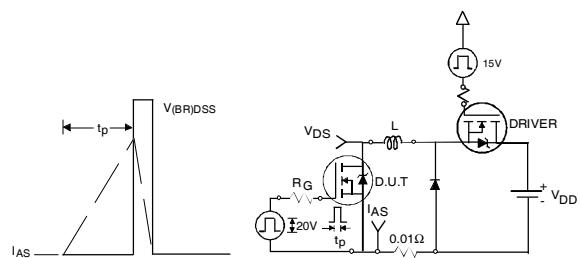
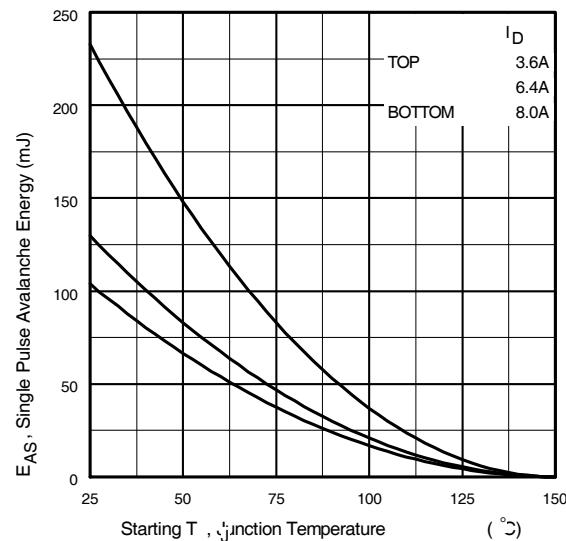
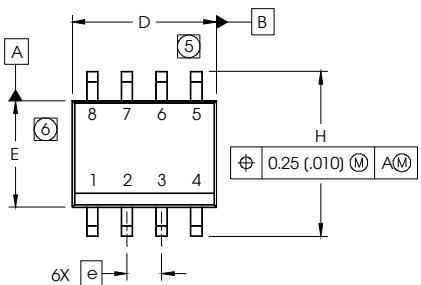


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

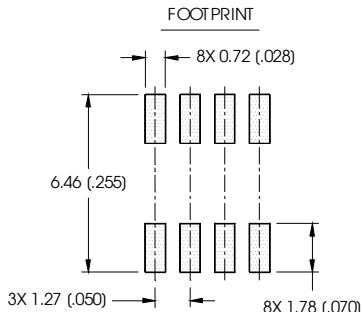
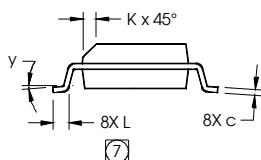
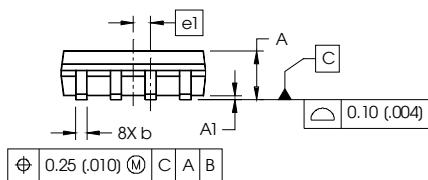
**Fig 12.** On-Resistance Vs. Drain Current**Fig 13.** On-Resistance Vs. Gate Voltage**Fig 14a&b.** Basic Gate Charge Test Circuit and Waveform**Fig 15a&b.** Unclamped Inductive Test circuit and Waveforms**Fig 15c.** Maximum Avalanche Energy Vs. Drain Current

SO-8 Package Outline(Mosfet & Fetky)

Dimensions are shown in millimeters (inches)



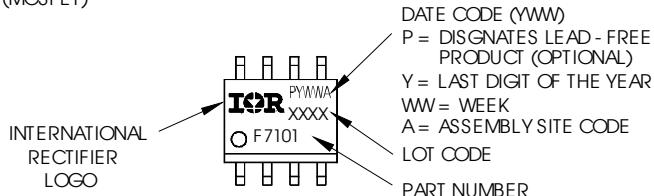
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



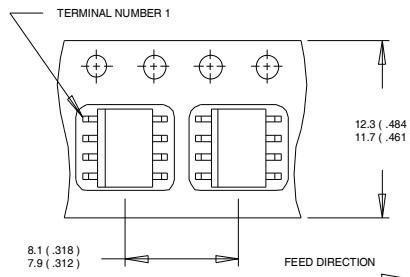
- NOTES:
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
 5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
 6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
 7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

SO-8 Part Marking Information

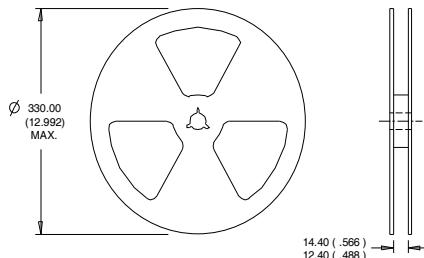
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

SO-8 Tape and Reel (Dimensions are shown in millimeters (inches))

NOTES:
 1. CONTROLLING DIMENSION : MILLIMETER.
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :
 1. CONTROLLING DIMENSION : MILLIMETER.
 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Qualification information[†]

Qualification level	Industrial (per JEDEC JESD47F ^{††} guidelines)	
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D ^{††})
RoHS compliant	Yes	

[†] Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

^{††} Applicable version of JEDEC standard at the time of product release

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$, $L = 3.2\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 8.0\text{A}$.
- ③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ When mounted on 1 inch square copper board, $t < 10$ sec

International
IR Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
 To contact International Rectifier, please visit <http://www.irf.com/photo-call/>